

Originator: null

Company: UMS

EPPL COMPONENT

Status: CLOSED

Accepted: 2010-09-14

EPPL Part:	2			
Group:	MICROCIRCUI	TS	Subgroup:	
Part type:				INTEGRATED CIRCUITS (MMIC)
	BES			
Description:	1µm Schottky d	liode process		
Detail spec:				
Package:	N/A			
Manufacturer:	UMS			
APPROVAL STATUS				
Qualification:	C	Others		
Other:				
Highest screening level (MIL)	: N	lo Qualification		
Evaluation programmes or other approvals:				
Former space usage:				
PREVIOUS PROCUREMENT AND TEST DATA				
Test data (Evaluation, Lot acceptance, DPA, MIL QCI/TCI,):				
RADIATION HARDNESS DATA				
Total dose effects:				
Displacement damage:				
Single event effects (SEL/SEU/SET/SEFI/SEB/SEGR/others):				
REMARKS				
It is the responsibility of the users to check that the process design can withstand the radiation requirements for its application				